

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	09/910,371	SEEM, JOHN E.	
	Examiner	Art Unit	Page 1 of 1
	Jeffrey R. West	2857	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,990,893	02-1991	Kiluk	340/573.1
*	B	US-2002/0124001	09-2002	Chaudhuri et al.	707/100
*	C	US-6,643,629	11-2003	Ramaswamy et al.	706/45
*	D	US-2001/0004726	06-2001	Lambrecht	702/5
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Carey et al., "Resistant and Test-Based Outlier Rejection: Effects on Gaussian One- and Two-Sample Inference". Technometrics, Vol. 39, No. 3. 1999.
*	V	Sematech, "The Engineers Statistics Internet (ESI) Handbook: Grubbs' Test for Outliers." 1999.
*	W	Rosner, "Percentage Points for a Generalized ESD Many-Outlier Procedure" Technometrics, Vol. 25, No 2. May 1983.
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.